

Notice of References CitedApplication/Control No.
09/898,321Applicant(s)/Patent Under
Reexamination
STREET ET AL.Examiner
Paul E Brock IIArt Unit
2815

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NON-PATENT DOCUMENTS

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	U	Mulato et al., "Simulated and measured data-line parasitic capacitance of amorphous silicon large-area image sensor arrays", J. Applied Physics, vol. 89, page 638 (2000)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.